

1. Record Nr.	UNISA996280327703316
Titolo	2017 IEEE 23rd International Symposium on On-Line Testing and Robust System Design (IOLTS) // Institute of Electrical and Electronics Engineers ; Panepistemio Athenon, contributor
Pubbl/distr/stampa	Piscataway, N.J. : , : IEEE, , 2017
ISBN	1-5386-0352-7
Descrizione fisica	1 online resource : illustrations
Disciplina	621.3815
Soggetti	Electronic circuit design Error-correcting codes (Information theory)
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Nota di bibliografia	Includes bibliographical references.
Sommario/riassunto	On line testing and more generally design for robustness, are important in modern electronic systems. These needs increased dramatically with the introduction of nanometer technologies, which impact adversely noise margins process, voltage and temperature variations aging and wear out soft error and EMI sensitivity and power density and make mandatory the use of design for robustness techniques for extending, yield, reliability, and lifetime of modern SoCs Design for reliability is also mandatory for reducing power dissipation, as reducing voltage for reducing power strongly affects reliability by reducing noise margins and thus the sensitivity to soft errors and EMI, and by increasing circuit delays which increase sensitivity to timing faults Design for Security is also strongly related with Design for Reliability, as security attacks are often fault based IOLTS is an established forum for presenting novel ideas and experimental data on these areas.